



Atty. Dkt. No. 083847-0198

IPW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Crocker et al.

Title: Nanometer-Scale Engineered Structures, Methods and Apparatus for Fabrication thereof, and Applications to Mask Repair, Enhancement, and Fabrication

Appl. No.: 10/689,547

Filing Date: 10/21/2003

Examiner: Ruggles

Art Unit: 1756

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.56

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Submitted herewith on Form PTO/SB/08 is a listing of documents known to Applicants in order to comply with Applicants' duty of disclosure pursuant to 37 CFR §1.56.

A copy of each non-U.S. patent document and each non-patent document is being submitted to comply with the provisions of 37 CFR §1.97 and §1.98.

The submission of any document herewith, which is not a statutory bar, is not intended as an admission that such document constitutes prior art against the claims of the present application or that such document is considered material to patentability as defined in 37 CFR §1.56(b). Applicants do not waive any rights to take any action which would be appropriate to antedate or otherwise remove as a competent reference any document which is determined to be a *prima facie* art reference against the claims of the present application.

TIMING OF THE DISCLOSURE

The listed documents are being submitted in compliance with 37 CFR §1.97(b), before the mailing date of the first Office Action on the merits.

RELEVANCE OF EACH DOCUMENT

Applicants respectfully request that the copending applications listed on the attached PTO-Form SB/08 be considered by the Examiner and be made of record in the present application and that, if necessary, any remarks be made of record.

All of the documents are in English.

Applicants respectfully request that each listed document be considered by the Examiner and be made of record in the present application and that an initialed copy of Form PTO/SB/08 be returned in accordance with MPEP §609.

The Commissioner is hereby authorized to charge any additional fees which may be required regarding this application under 37 CFR §§ 1.16-1.17, or credit any overpayment, to Deposit Account No. 19-0741. Should no proper payment be enclosed herewith, as by a check being in the wrong amount, unsigned, post-dated, otherwise improper or informal or even entirely missing, the Commissioner is authorized to charge the unpaid amount to Deposit Account No. 19-0741.

Respectfully submitted,

Date October 25, 2005

By J. Steven Rutt

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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

Date Submitted: October 25, 2005

(use as many sheets as necessary)

Sheet

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of

3

Complete if Known

Application Number	10/689,547
Filing Date	10/21/2003
First Named Inventor	Crocker
Group Art Unit	1756
Examiner Name	Ruggles

Attorney Docket Number 083847-0198

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
C1	4,160,049			Narcus	07-03-1979	
C2	5,104,684			Tao	04-14-1992	
C3	5,441,386			Hsieh	08-15-1995	
C4	5,980,998			Sharma et al.	11-09-1999	
C5	6,090,507			Grenon et al.	07-18-2000	
C6	6,096,459			Yang	08-01-2000	
C7	6,114,073			Yang	09-05-2000	
C8	6,396,966			Lewis et al.	05-28-2002	
C9	6,451,375			Cotte et al.	09-17-2002	
C10	6,455,175			Kozlov et al.	09-24-2002	
C11	6,827,979			Mirkin et al.	12-07-2004	
C12	2002/0009843			Kyushuo et al.	01-24-2002	
C13	2002/0122992			Kanamitsu et al.	09-05-2002	
C14	2003/0087200			Border et al.	05-08-2003	
C15	2003/0127441			Haight et al.	07-10-2003	
C16	2004/0127025			Crocker	07-01-2004	
C17	11/056,391			Zhang	02-14-2005	
C18	11/065,694			Cruchon-Dupeyrat	02-25-2005	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
	C19	ALI, M. B., et al., "Atomic Force Microscope Tip Nanoprinting of Gold Nanoclusters", Langmuir, vol. 18, pp. 872-876 (2002).	
	C20	BIERI, N. R., et al., "Microstructuring by printing and laser curing of nanoparticle solutions", Appl. Phys. Letts., vol. 82, no. 20, pp. 3529-3531 (2003).	
	C21	CHEN, K. M., et al., "Selective Self-Organization of Colloids on Patterned Polyelectrolyte Templates", Langmuir, vol. 16, pp. 7825-7834 (2000).	

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

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Substitute for form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT Date Submitted: October 25, 2005 (use as many sheets as necessary)				Complete if Known	
Sheet	2	of	3	Application Number	10/689,547
				Filing Date	10/21/2003
				First Named Inventor	Crocker
				Group Art Unit	1756
				Examiner Name	Ruggles
				Attorney Docket Number	083847-0198

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
	C22	CHIBA, A., et al., "Investigation of Pulsed Laser Removal of Cr and MoSi Film on a Quartz Substrate", Jpn. J. Appl. Phys., vol. 38, part 1, no. 12A, pp. 6577-6582 (1999)	
	C23	CHOU, S. Y., et al., "Imprint of sub-25 nm vias and trenches in polymers", Appl. Phys. Letters, vol. 67, no. 21, pp. 3114-3116 (1995).	
	C24	CORDELAIR, J., et al., "Electrical Characterization of Polymethylsiloxane/MoSi ₂ -Derived Composite Ceramics", J. Am. Ceram. Soc., vol. 84, no. 101, pp. 2256-59 (2001).	
	C25	FUJIKI, K., et al., "Preparation of a silica gel-carbon black composite by the sol-gel process in the presence of polymer-grated carbon black", J. Mater. Sci., vol. 33, no. 7, pp. 1871-1879 (1998).	
	C26	HECTOR, S., et al., "Review of progress in extreme ultraviolet lithography masks", J. Vac. Sci. Technol. B, vol. 19, no. 6, pp. 2612-2616 (2001).	
	C27	HIDBER, P. C., et al., "Microcontact Printing of Palladium Colloids: Micron-Scale Patterning by Electroless Deposition of Copper", Langmuir, vol. 12, pp. 1375-1380 (1996).	
	C28	KIM, J., et al., "Alternating phase shift mask defect printability for 130 nm and 100 nm KrF lithography", Intl. SEMATECH, (May 2000).	
	C29	MALTABES, J. G., et al., "Issues for Advanced Reticle Fabrication: (You want that reticle when?), Future Fab., Intl., Vol. 11, pp. (June 2001).	
	C30	MARTIN, J. E., et al., "Sintering of Alkanethiol-Capped Gold and Platinum Nanoclusters", J. Phys. Chem. B, vol. 107, pp. 430-434 (2003).	
	C31	MÜLLER, A. D., et al., "Localized electrochemical deposition of metals using micropipettes", Thin Solid Films, vol. 366, pp. 32-36 (2000).	
	C32	PECKERAR, M. C., et al., "Issues in Nanolithography for Quantum Effect Device Manufacture", Handbook of Microlithography, Micromachining, and Microfabrication, SPIE Optical Engineering Press, Bellingham, WA, Chptr. 8, vol. I, pp. 681-763 (1997).	
	C33	SENTURIA, S. D., MICROSYSTEM DESIGN, Kluwer Academic Publishers, Norwell, MA, pp. 50-57 (2001).	
	C34	SKINNER, J. G., et al., "Photomask Fabrication Procedures and Limitations", Handbook of Microlithography, Micromachining, and Microfabrication, SPIE Optical Engineering Press, Bellingham, WA, vol. I, Chptr. 5, pp. 377-474 (1997).	
	C35	STELLACCI, F., et al., "Laser and Electron-Beam Induced Growth of Nanoparticles for 2D and 3D Metal Patterning", Adv. Mater., vol. 14, no. 3, pp. 194-198 (2002).	
	C36	SU, M., et al., "Moving beyond Molecules: Patterning Solid-State Features via Dip-Pen Nanolithography with Sol-Based Inks", J. Am. Chem. Soc., vol. 124, no. 8, pp. 1560-1561 (2002).	

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	C37	TSUBOKAWA, N., et al., "Carbon Black/Alumina Gel Composite: Preparation by Sol-Gel Process in the Presence of Polymer-Grafted Carbon Black and Its Electric Properties", J. Poly. Sci. Part A-Polymer Chemistry, vol. 37, no. 18, pp. 3591-3597 (1999).	
	C38	WANG, X., et al., "Scanning Probe Contact Printing", Langmuir, vol. 19, pp. 8951-8955 (2003).	
	C39	WASSON, J. R., et al., "Writing, repairing, and inspecting of extreme ultraviolet lithography reticles considering the impact of the materials", J. Vac. Sci. Technol. B, vol. 19, no. 6, pp. 2635-2640 (2001).	
	C40	WILBUR, J. L., et al., "Microfabrication by Microcontact Printing of Self-Assembled Monolayers", Adv. Mater., vol. 6, no. 7/8, pp. 600-604 (1994).	
	C41	WILSON, O., et al., "Laser Writing in Polarized Silver Nanorod Films", Adv. Mater., vol. 14, no. 13, pp. 1000-1004 (2002).	
	C42	WOLF, S., et al., <u>Silicon Processing for the VLSI Era</u> , Lattice press, Sunset Beach, CA, pp. 485-486 (1986).	
	C43	WUELFING, W. P., et al., "Monolayer-Protected Clusters: Molecular Precursors to Metal Films", Chem. Mater., vol. 13, pp. 87-95 (2001).	
	C44	ZHANG, W., et al., "Multilevel nanoprint lithography with submicron alignment over 4 in. Si wafers", Appl. Phys. Letts., vol. 79, no. 6, pp. 845-847 (2001).	

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